The Price of Tolerance in Distribution Testing

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WALD(O) 2021

(Joint work with Ayush Jain (UCSD), Gautam Kamath (U Waterloo), and Jerry Li (MSR))



Given m i.i.d. samples from some unknown p over [n], a reference q, and distance parameter ϵ , distinguish between

- Completeness: p = q
- Soundness: TV(p,q) ≥ ε

with probability at least 1/10, where

$$TV(p,q) := \sup(p(S) - q(S)) = \frac{1}{2} \ell_1(p,q)$$

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Identity testing/one-sample goodness-of-fit

[GR00, BFFKRW01, Pan08, VV14, DKN15, ADK15, DGPP18...]

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$$m = \Theta(\sqrt{n/\epsilon^2})$$

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Given m i.i.d. samples from some unknown p over [n], a reference q, and distance parameter ϵ , distinguish between

- Completeness: TV(p,q) = 0
- Soundness: TV(p,q) ≥ ε

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Given m i.i.d. samples from some unknown p over [n], a reference q, and distance parameters ε_1 , ε_2 , distinguish between

- Completeness: $TV(p,q) \le \varepsilon_1$
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Tolerant identity testing

[PRR06,VV10,VV11,HJW16,JVHW17,JHW18...]

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Tolerant identity testing

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Not quite.

$$O(n/((\epsilon_2-\epsilon_1)^2\log n))$$

 $\Theta(n/\log n)$ for constant $\varepsilon_1 < \varepsilon_2$

 $\Omega(\sqrt{n/\epsilon_2^2})$ always

 $\Omega(n/((\epsilon_2-\epsilon_1)^2\log n))$ for distance estimation

$$O(\sqrt{n/\epsilon_2^2})$$

for $\epsilon_1 \le \epsilon_2/\sqrt{n}$

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 $\Theta(n/\log n)$ for **constant** $\varepsilon_1 < \varepsilon_2$



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Tight sample complexity* as a function of n, ε_2 , ε_1 , in all parameter regimes.

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$$\tilde{\Theta}\left(\frac{\sqrt{n}}{\varepsilon_2^2} + \frac{n}{\log n} \cdot \max\left\{\frac{\varepsilon_1}{\varepsilon_2^2}, \left(\frac{\varepsilon_1}{\varepsilon_2^2}\right)^2\right\}\right)$$

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Some remarks

New result even in the "low tolerance" regime: Cauchy—Schwarz wasn't tight!

$$Θ(νn/ε22)$$
 $Θ(νn/ε22)$ for $ε1≤ε2/νn$ for $ε1≤1/νn$

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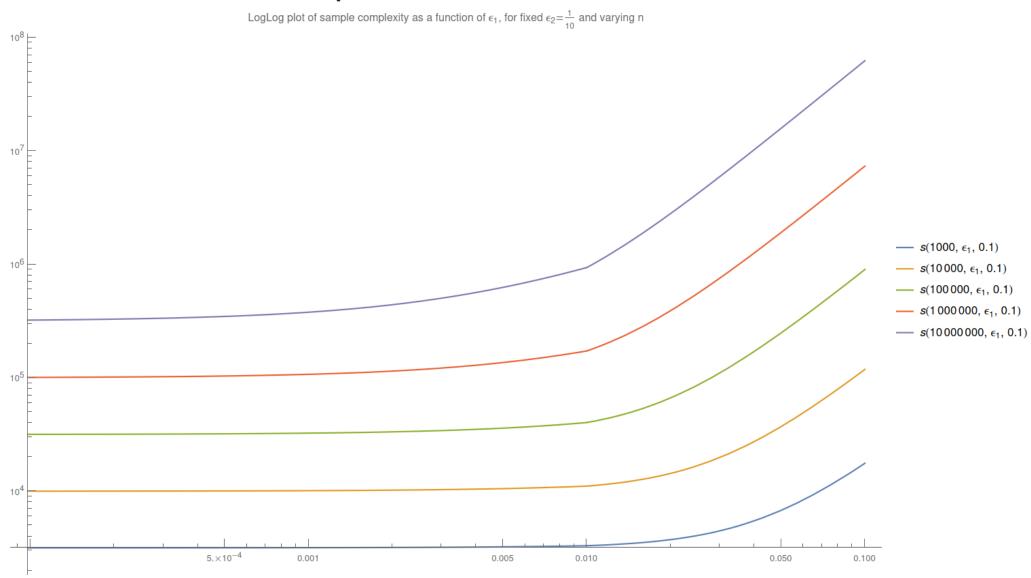
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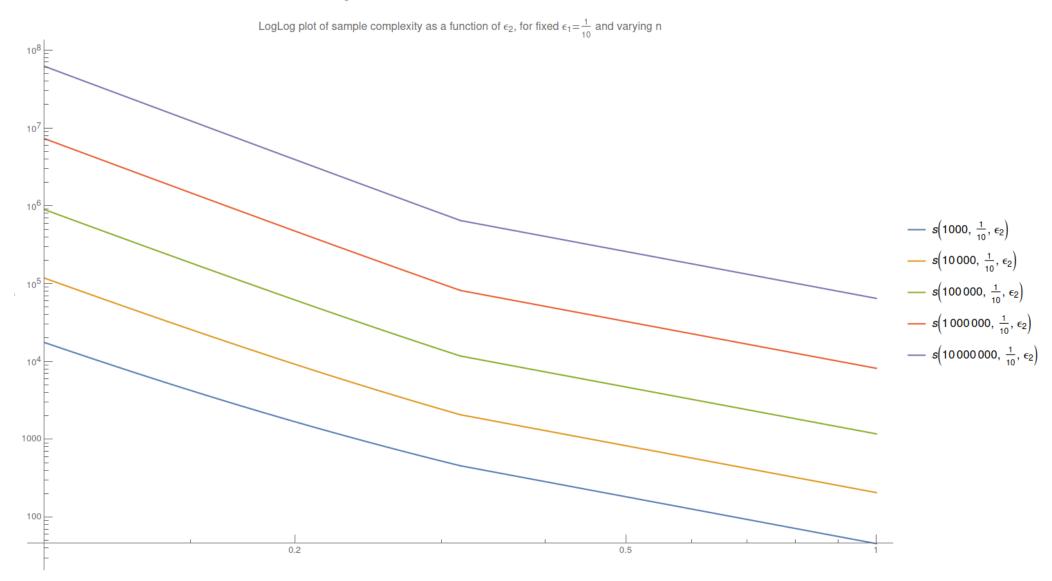
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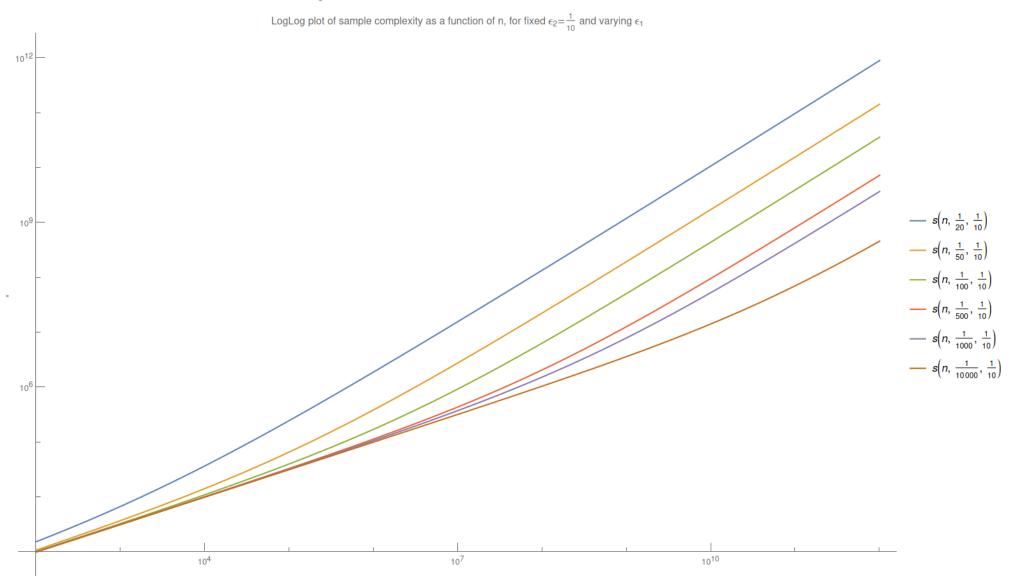
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More remarks

Can use our results on tolerant **identity** and **closeness** to obtain tolerant testing for/under **structure**:

- Monotonicity, unimodality, log-concavity, independence
- Under structural assumptions ("A_k distances")
- Instance-optimal tolerant testing
- (insert favourite property here)

Upper bounds via carefully **rescaled** χ^2/ℓ_2 -type tester

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Algorithm 1 Tolerant testing algorithm.

Require: $0 \le \varepsilon_1 < \varepsilon_2 \le 1$, m, n, two sets of Poi(m) samples from both p and q Set the threshold

$$\tau \leftarrow c \cdot \min\left(\frac{m^{3/2}\varepsilon_2}{n^{1/2}}, \frac{m^2\varepsilon_2^2}{n}\right)$$

Compute Z from the sets of samples, as per (1). if $Z \ge \tau$ then return $||p - q||_1 \ge \varepsilon_2$ else return $||p - q||_1 \le \varepsilon_1$ end if

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$$\widehat{f_i} := \begin{cases} \max \left\{ \frac{|\tilde{X}_i - \tilde{Y}_i|}{\sqrt{m/n}}, \frac{\tilde{X}_i + \tilde{Y}_i}{m/n}, 1 \right\} & \text{if } m \ge n \\ \max \{\tilde{X}_i + \tilde{Y}_i, 1\} & \text{if } m < n. \end{cases}$$

 $Z_i := (X_i - Y_i)^2 - X_i - Y_i$

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Does not require knowledge of ε_1 !

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- Write this as an LP
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- Try to lower bound the dual's optimal value
 - Weep (i), as the asymmetry (testing, not estimation!) rules out using the same polynomial uniform approximation results as in [WY]
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^{**} And closeness.



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